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| Notice of References Cited | Application/Control No. 10/709,784 | Applicant(s)/Patent Under Reexamination CHAN ET AL. | |
| | Examiner Don P. Le | Art Unit 2819 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| | A | US-6,624,679 | 09-2003 | Tomaiuolo et al. | 327/262 |
| | B | US-6,407,601 | 06-2002 | Lin, Jung-Chen | 327/158 |
| | C | US-6,359,477 | 03-2002 | Pathak, Rajesh | 327/112 |
| | D | US-5,532,969 | 07-1996 | Houghton et al. | 365/226 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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